

Single-Channel Silicon ESD Protection Devices



Silicon ESD (SESD) devices help provide protection and improve reliability for applications including consumer, portable and mobile electronics. The 0402- and 0201-sized devices have low capacitance of 0.10pF for bi-directional devices and 0.20pF for uni-directional devices with low insertion loss. This helps provide protection for high-speed data signals. The single-channel SESD devices provide robust ESD protection with industry-leading 20kV contacts and air discharge ratings per IEC61000-4-2 standard. The ultra-low capacitance enables signal integrity for today's highest-speed interfaces including USB 3.0/2.0, HDMI, eSATA, DisplayPort and Thunderbolt.

TE offers the single-channel devices in uni-directional and bi-directional configurations. Bi-directional devices offer the lowest capacitance and insertion loss, allow placement on the PCB without orientation constraint and do not clip signals that swing below ground. Uni-directional devices offer a low negative breakover voltage and help provide protection for high-speed digital interfaces. The 0201-sized XDFN small footprint — measuring a mere 0.6mm x 0.3mm x 0.31mm — offers designers placement flexibility in space-constrained applications.



Benefits

- Low capacitance provides low insertion loss for high speed data signals
- Provides ESD protection up to 20kV contact and air discharge per IEC61000-4-2
- Small size ESD protection diodes for high-speed data signals (0402- and 0201-size devices)
- Helps protect electronic circuits against damage from Electrostatic Discharge (ESD), lightning and cable discharge events
- Assists equipment to pass IEC61000-4-2, level 4 testing

Features

- Low capacitance: at 0.10pF (typ, bi-di) and at 0.20 pF (typ, uni-di)
- Low leakage current: 50nA @ 5V (max)
- Low clamping voltage: +10.0 / - 10.V (typ, bi-di) +9.20 / -0.8V (typ, uni-di) @ (tp=8x20μs, Ipp=2A)
- ESD: 20kV contact / air discharge per IEC61000-4-2
- Surge: 2A (max) @ (tp=8x20μs) per IEC61000-4-5
- Small size and low profile: XDFN packages
- RoHS compliant, Pb and halogen free (refers to: Br≤900ppm, Cl≤900ppm, Br + Cl≤1500ppm)

Applications

- Consumer, mobile and portable electronics
- Tablet PC and external storage with high-speed interfaces
- High-speed data lines
- USB 3.0/2.0, HDMI 1.3/1.4, DisplayPort interface, Thunderbolt interface (Light Peak), V-by-One HS, and LVDS interface
- Applications requiring high ESD performance in small packages

Table SE1 Device Maximum Ratings

Part Number	ESD Withstand* (IEC 61000-4-2, level 4)		Temperature		Peak Current ($t_p=8 \times 20 \mu s$)
	Contact (kV)	Air (kV)	Operating (°C)	Storage (°C)	I _{pp} (A)
SESD0201X1UN-0020-090	± 20	± 20	-55 to +125	-55 to +150	2.0
SESD0402X1UN-0020-090	± 20	± 20	-55 to +125	-55 to +150	2.0
SESD0201X1BN-0010-098	± 20	± 20	-55 to +125	-55 to +150	2.0
SESD0402X1BN-0010-098	± 20	± 20	-55 to +125	-55 to +150	2.0

- * 20kV @ 1 pulse; 10kV @ 100 pulses; 8kV @ 1,000 pulses (under IEC6100-4-2)
- Maximum leakage current post 15kV & 20kV pulses is less than 1 μA
 - Device maximum rating @ T = 25°C, unless otherwise specified
 - Caution: Stress exceeding Device Maximum Ratings may damage the device
 - Prolonged exposure to stresses above the recommended operating conditions may affect device reliability

Table SE2 Device Electrical Characteristics @ T = 25°C

Part Number	Input Capacitance*		Breakdown Voltage (Typ)	Reverse Working Voltage (V)		Reverse Leakage Current (Typ)	Clamping Voltage (Typ)
	Typical (pF)	Maximum (pF)	V _{BR} @ I _T =1mA (V)	Min	Max	I _L @ V _{RWM} =5.0V (nA)	V _{CL} @ I _{pp} =2.0A (V)
SESD0201X1UN-0020-090	0.20	0.25	+9.00 / -0.80	0	+7.00	25.0	+9.20 / -0.80
SESD0402X1UN-0020-090	0.20	0.25	+9.00 / -0.80	0	+7.00	25.0	+9.20 / -0.80
SESD0201X1BN-0010-098	0.10	0.13	+9.80 / -9.80	-7.00	+7.00	25.0	+10.0 / -10.0
SESD0402X1BN-0010-098	0.10	0.13	+9.80 / -9.80	-7.00	+7.00	25.0	+10.0 / -10.0

* @ V_R = 0V, f = 3GHz

8

Figures SE1-SE2 Device IV Characteristics

Figure SE1

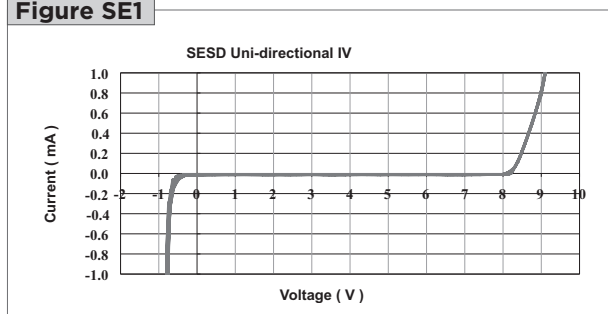
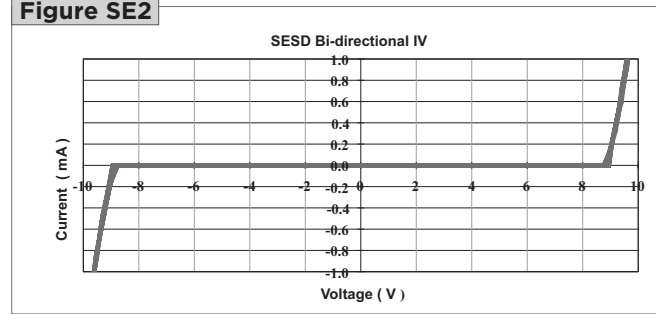


Figure SE2



Figures SE3-SE4 Insertion Loss Diagrams

Application / Protocols	Bit Rate (Gbps)	@Freq (GHz)	Ins. Loss (dB)
HDMI 1.4 (1080P)	2.25	1.13	-0.23
DisplayPort	2.70	1.35	-0.26
HDMI 1.4 (4K / QuadHD)*	3.40	1.70	-0.30
USB 3.0	5.00	2.50	-0.38
eSATA	6.00	3.00	-0.44
Thunderbolt	10.0	5.00	-0.69

* HDMI 4K / QuadHD resolutions (4096 x 2160) ready

Figures SE3-SE4 Insertion Loss Diagrams

Cont'd

Figure SE3

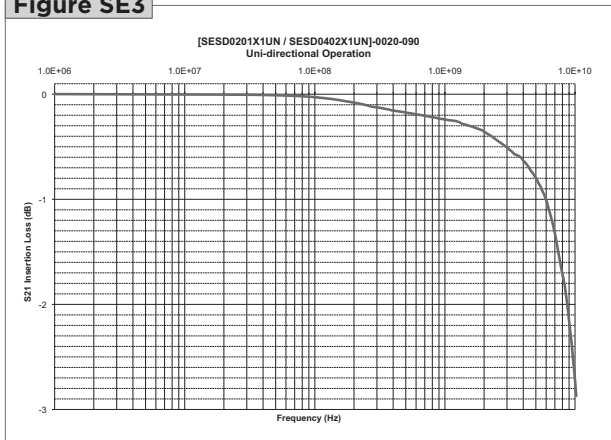
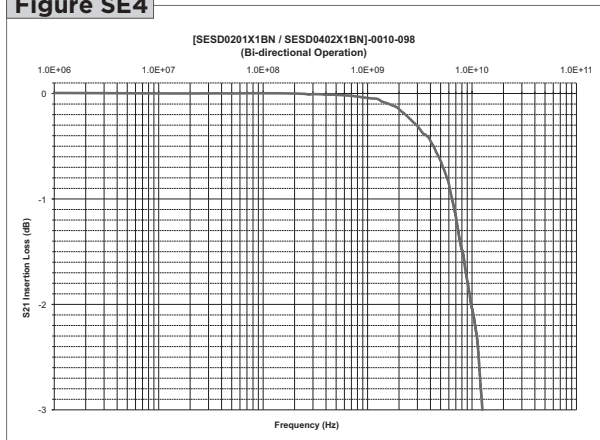


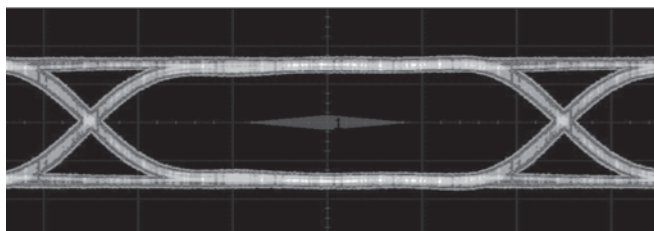
Figure SE4



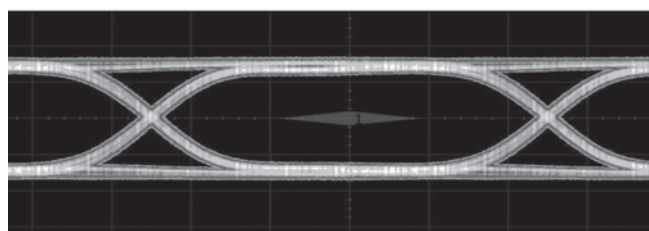
Figures SE5-SE7 Eye Diagrams

Figure SE5

USB 3.0 Eye Diagrams
5.0 Gb/s, 1000mV differential, CPO Compliant Test Pattern



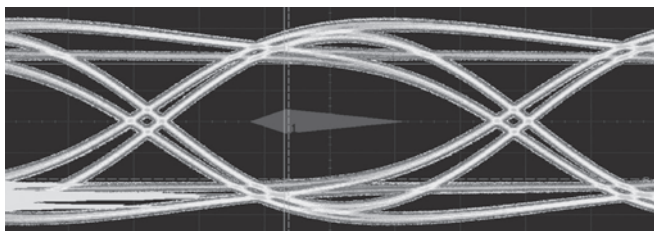
Without SESD Device



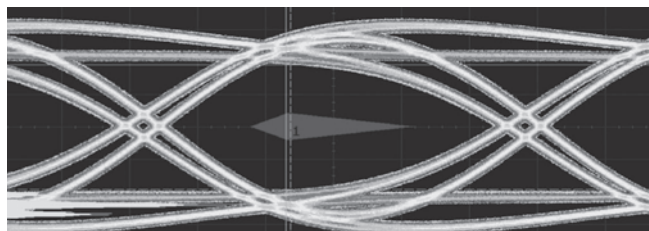
With SESD Device

Figure SE6

DisplayPort Eye Diagrams
5.4 Gb/s, 800mV differential, PRBS7 Compliant Test Pattern, SSC Enabled



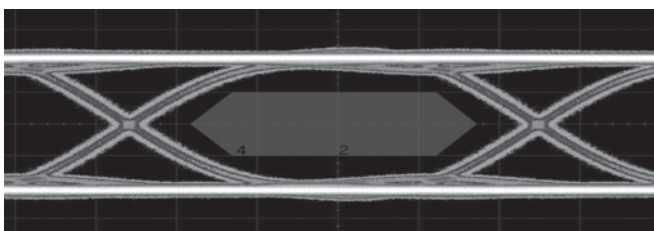
Without SESD Device



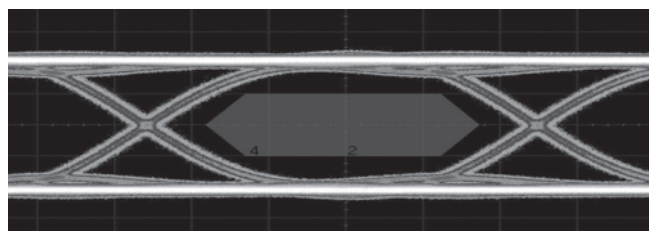
With SESD Device

Figure SE7

HDMI Eye Diagrams
3.4 Gb/s, 990 mV differential, TMDS Data



Without SESD Device



With SESD Device

Table SE3 Dimensions for SESD Devices in Millimeters and (Inches)
Part Number
SESD0201X1UN-0020-090

A			A ₁			A ₃			D			E		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.28	0.30	0.32	0	–	0.05	–	0.102 ref.	–	0.25	0.30	0.35	0.55	0.60	0.65
(0.011)	(0.012)	(0.013)	(0)	–	(0.002)	–	(0.004 ref.)	–	(0.010)	(0.012)	(0.014)	(0.022)	(0.024)	(0.026)

K			b			L ₁			L ₂			e			Figure
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.11	0.17	0.22	0.20	0.25	0.30	0.13	0.18	0.23	0.14	0.19	0.24	–	0.356 BSC*	–	SE8
(0.004)	(0.007)	(0.009)	(0.008)	(0.010)	(0.012)	(0.005)	(0.008)	(0.009)	(0.006)	(0.007)	(0.009)	–	(0.014 BSC*)	–	

* BSC — Basic Spacing between Centers

Part Number
SESD0201X1BN-0010-098

A			A ₁			A ₃			D			E		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.28	0.30	0.32	0	–	0.05	–	0.102 ref.	–	0.25	0.30	0.35	0.55	0.60	0.65
(0.011)	(0.012)	(0.013)	(0)	–	(0.002)	–	(0.004 ref.)	–	(0.010)	(0.012)	(0.014)	(0.022)	(0.024)	(0.026)

K			b			L ₁			L ₂			e			Figure
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.11	0.17	0.22	0.20	0.25	0.30	0.13	0.18	0.23	0.14	0.19	0.24	–	0.356 BSC*	–	SE9
(0.004)	(0.007)	(0.009)	(0.008)	(0.010)	(0.012)	(0.005)	(0.008)	(0.009)	(0.006)	(0.007)	(0.009)	–	(0.014 BSC*)	–	

* BSC — Basic Spacing between Centers

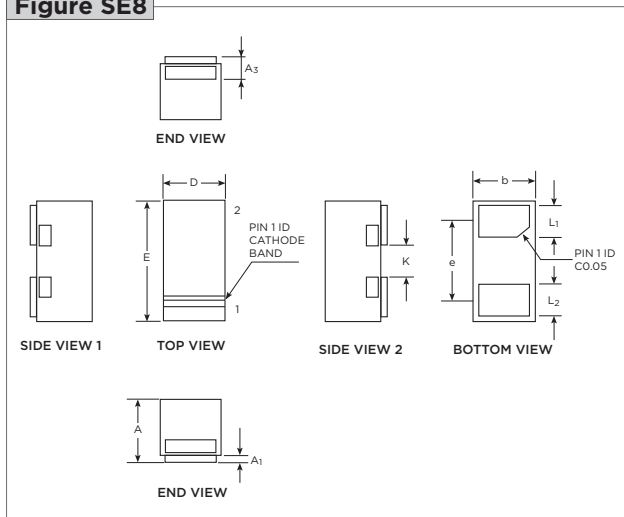
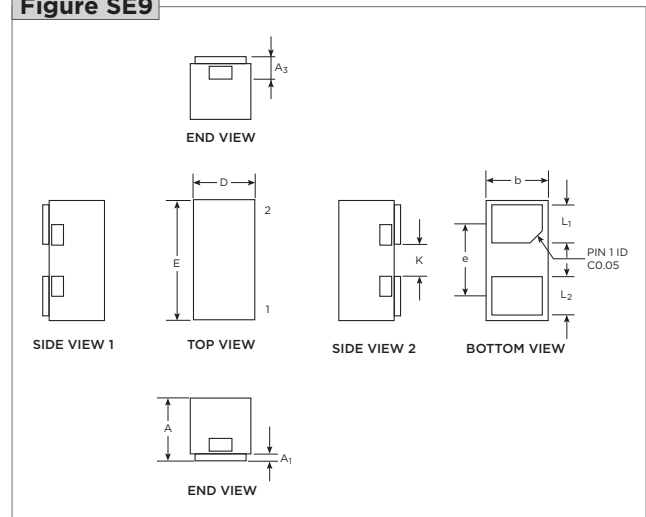
Figure SE8

Figure SE9


Table SE4 Dimensions for SESD Devices in Millimeters and (Inches)
Part Number
SESD0402X1UN-0020-090

A			A ₁			A ₃			D			E		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.33	0.38	0.43	0	-	0.05	-	0.13 ref.	-	0.55	0.60	0.65	0.95	1.00	1.05
(0.013)	(0.015)	(0.017)	(0)	-	(0.002)	-	(0.005 ref.)	-	(0.022)	(0.024)	(0.026)	(0.037)	(0.039)	(0.041)

K			b			L			e			Figure
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.35	0.40	0.45	0.45	0.50	0.55	0.20	0.25	0.30	-	0.65 BSC*	-	SE10
(0.014)	(0.016)	(0.018)	(0.018)	(0.020)	(0.022)	(0.008)	(0.010)	(0.012)	-	(0.026 BSC*)	-	

* BSC — Basic Spacing between Centers

Part Number
SESD0402X1BN-0010-098

A			A ₁			A ₃			D			E		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.33	0.38	0.43	0	-	0.05	-	0.13 ref.	-	0.55	0.60	0.65	0.95	1.00	1.05
(0.013)	(0.015)	(0.017)	(0)	-	(0.002)	-	(0.005 ref.)	-	(0.022)	(0.024)	(0.026)	(0.037)	(0.039)	(0.041)

K			b			L			e			Figure
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.35	0.40	0.45	0.45	0.50	0.55	0.20	0.25	0.30	-	0.65 BSC*	-	SE11
(0.014)	(0.016)	(0.018)	(0.018)	(0.020)	(0.022)	(0.008)	(0.010)	(0.012)	-	(0.014 BSC*)	-	

* BSC — Basic Spacing between Centers

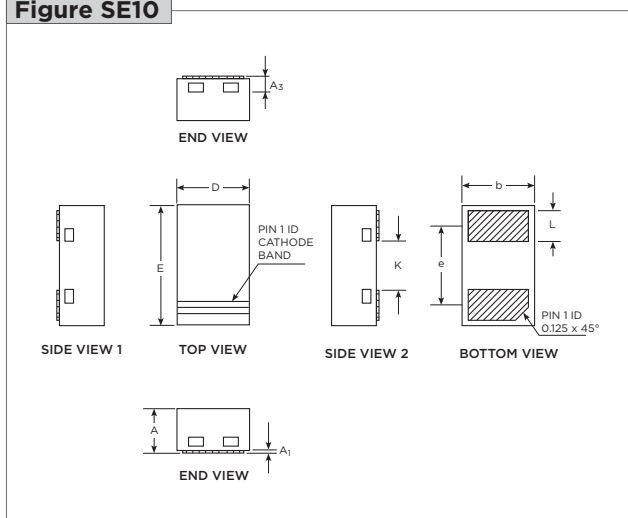
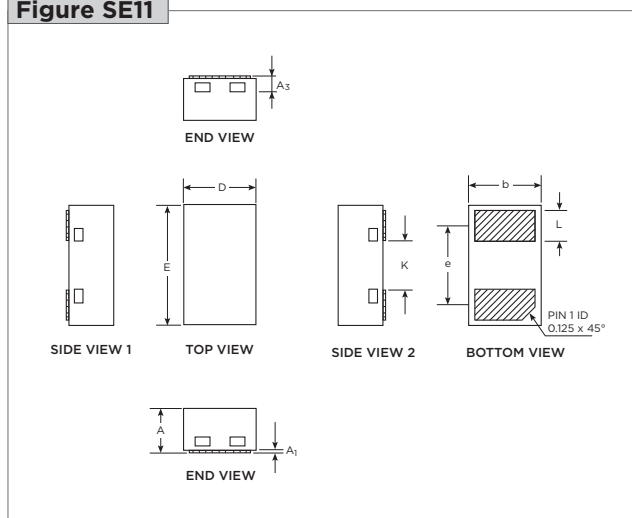
Figure SE10

Figure SE11


Table SE5 SESD Landing Pad Layout for O201 Package

Symbol	Millimeters (mm)	Inches (in)
A	0.32	0.013
B	0.62	0.024
D	0.24	0.009
F	0.14	0.006

Figure SE12

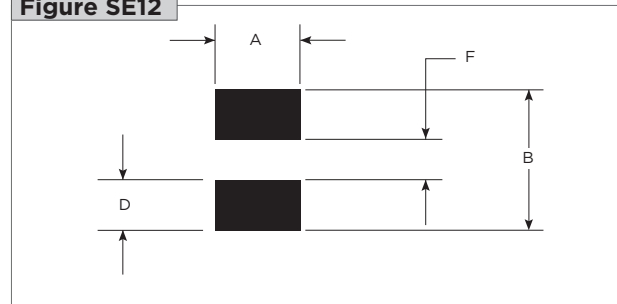
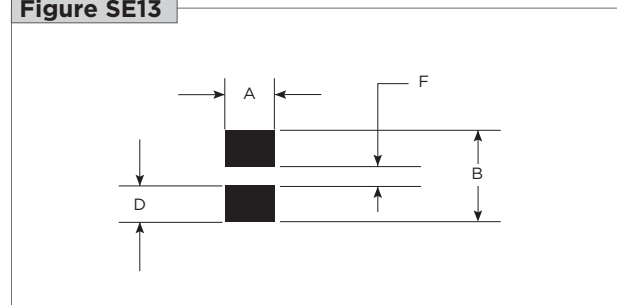


Table SE6 SESD Landing Pad Layout for O402 Package

Symbol	Millimeters (mm)	Inches (in)
A	0.60	0.024
B	1.00	0.039
D	0.35	0.014
F	0.30	0.012

Figure SE13



8

Table SE7 Solder Reflow Recommendations for SESD Devices

A	Temperature Ramp-up 1	From Ambient to Preheating Temperature	30s to 60s
B	Preheating	140°C - 160°C	60s to 120s
C	Temperature Ramp-up 2	From Preheating to Main Heating Temperature	20s to 40s
D	Main Heating	at 200°C at 220°C at 240°C at 260°C	60s to 70s 50s to 60s 30s to 40s 5s to 10s
E	Cooling	From Main Heating Temperature to 100°C	4°C/s max

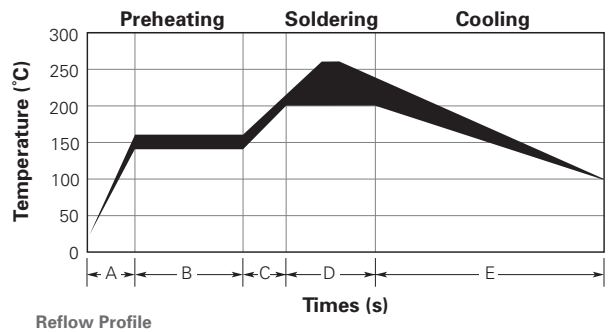


Table SE8 Carrier Tape Specifications

Tape Dimension EIA Mark	SESD0201		SESD0402	
	Dimension (mm)	Tolerance	Dimension (mm)	Tolerance
W	8.00	±0.10	8.00	±0.10
P ₀	4.00	±0.10	4.00	±0.10
P ₁	2.00	±0.10	2.00	±0.10
P ₂	2.00	±0.05	2.00	±0.05
A ₀	0.36	±0.03	0.70	±0.05
B ₀	0.66	±0.03	1.15	±0.05
D ₀	Ø1.50	-0.00 / +0.10	Ø1.55	±0.05
D ₁	Ø0.20	±0.05	Ø0.40	±0.05
E ₁	1.75	±0.10	1.75	±0.10
F	3.50	±0.05	3.50	±0.05
K ₀	0.33	±0.03	0.47	±0.05
T	0.23	±0.02	0.20	±0.05
Detail A	-	2° (max)	-	3° (max)

Note 1. All dimensions in mm

Note 2. Measured from centerline of pocket to centerline of sprocket hole

Note 3. Cumulative tolerance of 10 sprocket holes is ±0.20

Note 4. Tolerances unless noted ±0.20

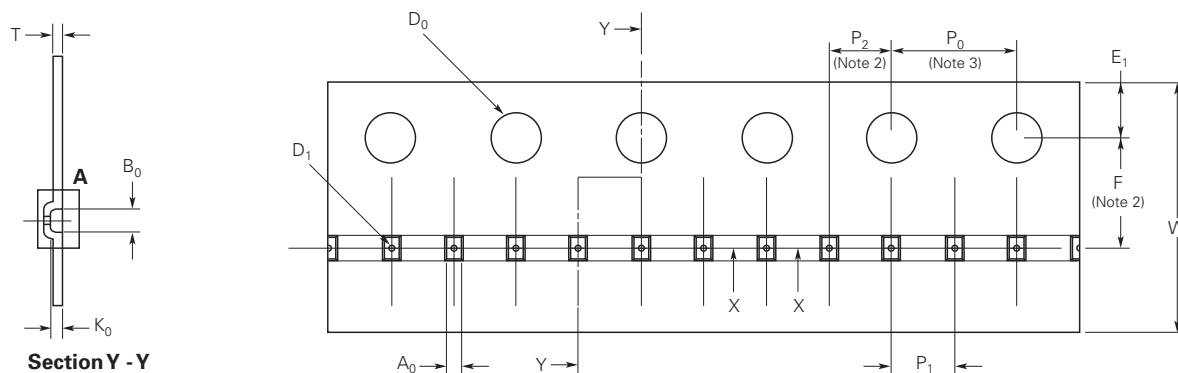
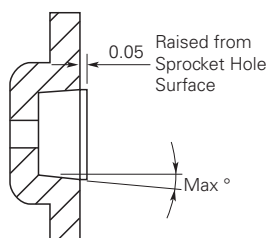
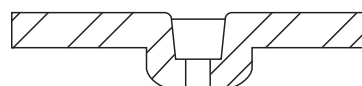
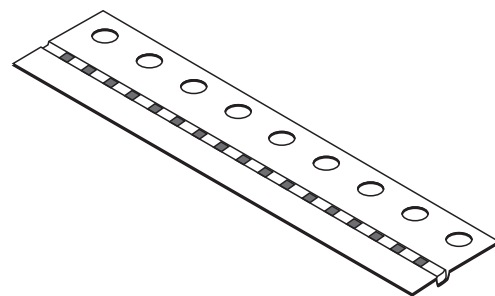
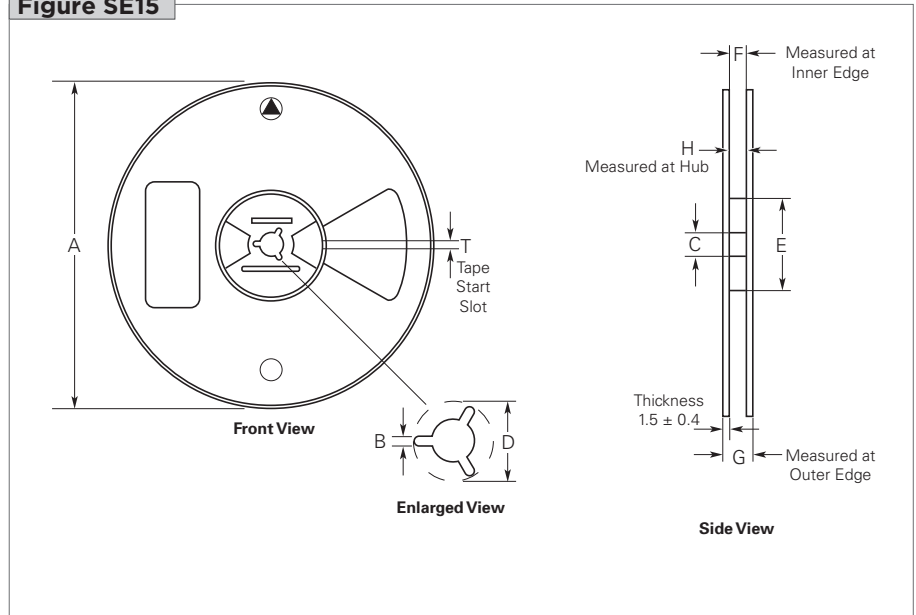
Figure SE14

Section Y - Y

Detail A

Section X - X


Table SE9 Reel Specifications

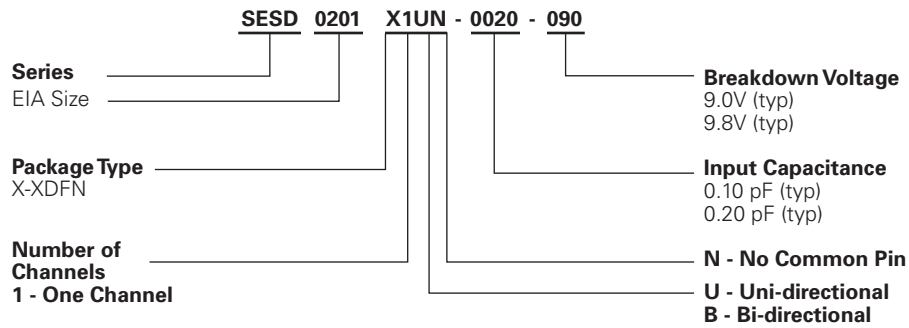
Reel Dimension	Dimension (mm)
EIA Mark	
A	180 ± 2.00
B	1.50 (min)
C	13.10 ± 0.20
D	20.20 (min)
E	60 ± 1.00
F	8.75 ± 1.00
G	11.6 ± 1.00
H	9.4 (max)

Figure SE15



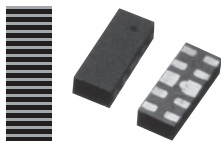
Part Numbering System for Single-Channel Silicon ESD Devices

8



Part Marking

Part Number	Part Marking
SESD0201X1UN-0020-090	C
SESD0402X1UN-0020-090	C
SESD0201X1BN-0010-098	C
SESD0402X1BN-0010-098	C

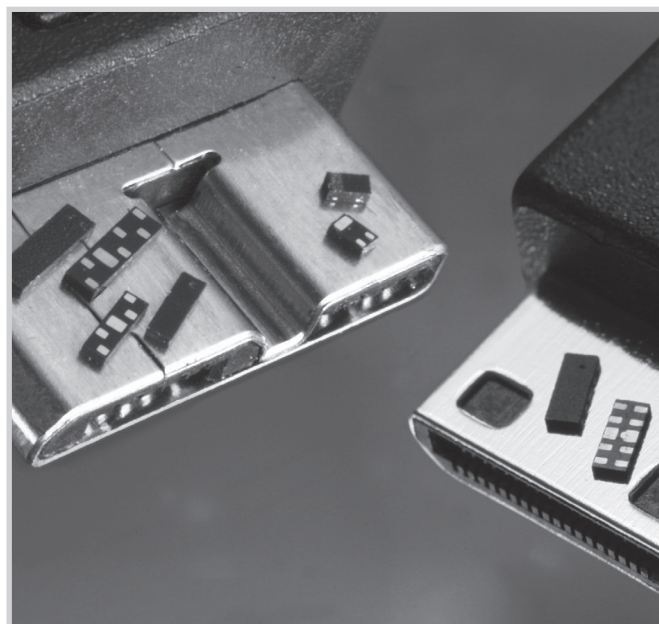


Multi-Channel Silicon ESD Flow-Through Arrays



The Silicon ESD (SESD) arrays can help provide protection and improve reliability of electronics in applications including but not limited to consumer, portable and mobile electronics. The multi-channel SESD flow-through arrays have low capacitance of 0.20pF with low insertion loss, which help protect high-speed data signals. The SESD arrays provide robust ESD protection with 20kV contact and air discharge rating per the IEC61000-4-2 standard. The low capacitance SESD arrays enable signal integrity for today's highest-speed interfaces including USB 3.0/2.0, HDMI, eSATA, DisplayPort and Thunderbolt.

TE offers four- and six-channel miniature arrays which are up to 85% smaller than common multi-channel arrays for space-constrained applications. TE's ultra-small packages have lower parasitic impedance which reduces insertion loss at high frequencies compared to larger-packaged devices. All of TE's SESD arrays are in flow-through design packages which allow for matched impedance PCB trace routing essential for high-speed signal integrity.



Benefits

- Low capacitance; provides low insertion loss for high-speed data signals
- Provides ESD protection up to 20kV contact and air discharge per IEC61000-4-2
- Industry's smallest footprint and lowest profile multi-channel ESD arrays helps to optimize board space
- Flow-through and single connection design helps routing PCB matched impedance high-speed data lines
- Helps protect electronic circuits against damage from Electrostatic Discharge (ESD), lightning and cable discharge events
- Helps assist equipment to pass IEC61000-4-2, level 4 testing

Applications

- Consumer, mobile and portable electronics
- Tablet PC and external storage with high-speed; also below: ultra-high-speed interfaces
- Ultra-high-speed data lines
- USB 3.0/2.0, HDMI 1.3/1.4, DisplayPort interface, Thunderbolt interface (Light Peak), V-by-One HS, and LVDS interface
- Applications requiring high ESD performance in small DFN packages

Features

- Low Capacitance: at 0.20pF (typ, 200pF)
- Low leakage current : 25nA @ 5V (typ)
- Low clamping voltage: +9.20 / - 0.8V (typ) (tp=8x20μs, Ipp=2A)
- ESD 20kV Contact and air discharge maximum rating per IEC61000-4-2
- Surge: 2A (max) @ (tp=8x20μs) per IEC61000-4-5
- Small size and low profile: XDFN array package 0.38mm height
- RoHS Compliant, Pb and Halogen Free (refers to: Br≤900ppm, Cl≤900ppm, Br + Cl≤1500ppm)

Table ME1 Device Maximum Ratings

Part Number	ESD Withstand* (IEC 61000-4-2, level 4)		Temperature		Peak Current (tp=8x20μs)
	Contact (kV)	Air (kV)	Operating (°C)	Storage (°C)	I _{pp} (A)
SESD0402Q2UG-0020-090 (2-ch)	±20	±20	-55 to +125	-55 to +150	2.0
SESD0802Q4UG-0020-090 (4-ch)	±20	±20	-55 to +125	-55 to +150	2.0
SESD1004Q4UG-0020-090 (4-ch)	±20	±20	-55 to +125	-55 to +150	2.0
SESD1103Q6UG-0020-090 (6-ch)	±20	±20	-55 to +125	-55 to +150	2.0

- * 20kV @ 1 pulse; 10kV @ 100 pulses; 8kV @ 1,000 pulses (under IEC6100-4-2)
- Maximum leakage current post 15kV and 20kV pulses is less than 1μA
 - Device maximum rating @T=25°C, unless otherwise specified
 - Caution: Stress exceeding Device Maximum Ratings may damage the device
 - Prolonged exposure to stresses above the recommended operating conditions may affect device reliability

Table ME2 Device Electrical Characteristics @ T = 25°C

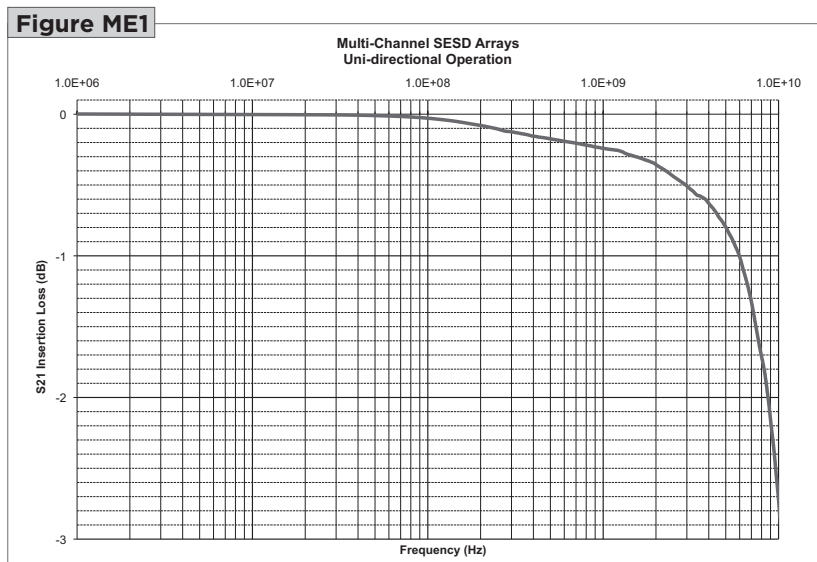
Part Number	Input Capacitance*		Breakdown Voltage (Typ)	Reverse Working Voltage (V)		Reverse Leakage Current (Typ)	Clamping Voltage (Typ)
	Typ (pF)	Max (pF)	V _{BR} @ I _T =1mA (V)	Min	Max	I _L @ V _{RWM} =5.0V (nA)	V _{CL} @ I _{pp} =2.0V (V)
SESD0402Q2UG-0020-090 (2-ch)	0.20	0.25	+9.00 / -0.80	0	+7.00	25.0	+9.20 / -0.80
SESD0802Q4UG-0020-090 (4-ch)	0.20	0.25	+9.00 / -0.80	0	+7.00	25.0	+9.20 / -0.80
SESD1004Q4UG-0020-090 (4-ch)	0.20	0.25	+9.00 / -0.80	0	+7.00	25.0	+9.20 / -0.80
SESD1103Q6UG-0020-090 (6-ch)	0.20	0.25	+9.00 / -0.80	0	+7.00	25.0	+9.20 / -0.80

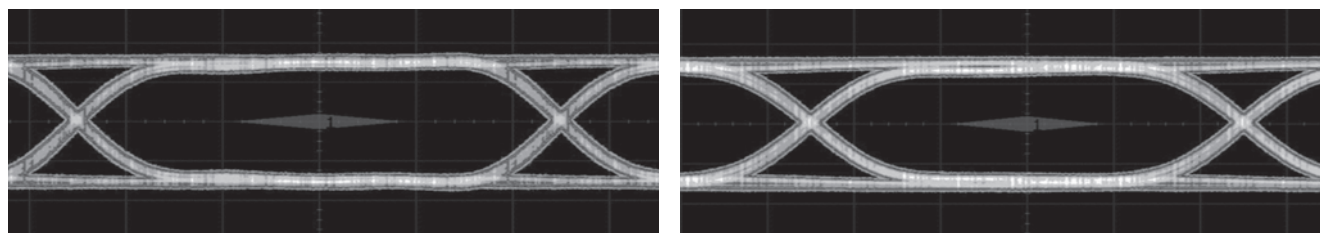
* @V_R=0V, f=3GHz

Table ME3 Insertion Loss Diagrams

Application / Protocol	Bit Rate (Gbps)	@Freq (GHz)	Ins. Loss (dB)
HDMI 1.4 (1080P)	2.25	1.13	-0.23
DisplayPort	2.70	1.35	-0.26
HDMI 1.4 (4K / QuadHD)*	3.40	1.70	-0.30
USB 3.0	5.00	2.50	-0.38
eSATA	6.00	3.00	-0.44
Thunderbolt	10.0	5.00	-0.69

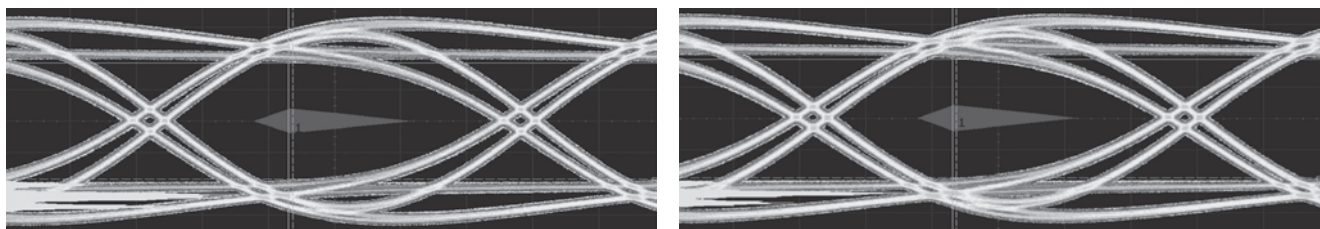
* HDMI 4K / QuadHD resolutions (4096 x 2160) ready



Figures ME2-ME4 Eye Diagrams
Figure ME2
USB 3.0 Eye Diagrams
 5.0Gb/s, 1000mV Differential, CPO Compliant Test Pattern


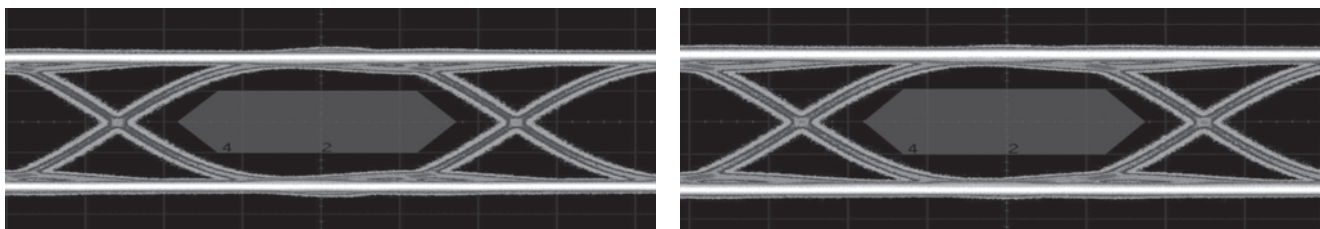
Without SESD Device

With SESD Device

Figure ME3
DisplayPort Eye Diagrams
 5.4Gb/s, 800mV Differential, PRBS7 Compliant Test Pattern, SSC Enabled


Without SESD Device

With SESD Device

Figure ME4
HDMI Eye Diagrams
 3.4Gb/s, 990 mV Differential, TMDS Data


Without SESD Device

With SESD Device

Table ME4 Device Dimensions for SESD Devices in Millimeters and (Inches)

Part Number
SESD0402Q4UG-0020-090

A			A ₁			A ₃			D			E			K		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.33	0.38	0.43	0	-	0.05	-	0.13 ref.	-	0.55	0.60	0.65	0.95	1.00	1.05	0.35	0.40	0.45
(0.013)	(0.015)	(0.017)	(0)	-	(0.002)	-	(0.005 ref.)	-	(0.022)	(0.024)	(0.026)	(0.037)	(0.039)	(0.041)	(0.014)	(0.016)	(0.018)

L ₁			L ₂			b			e ₁			e ₂			Figure
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.45	0.50	0.55	0.20	0.25	0.30	0.10	0.15	0.20	-	0.35 BSC*	-	-	0.65 BSC*	-	ME5
(0.018)	(0.020)	(0.022)	(0.008)	(0.010)	(0.012)	(0.004)	(0.006)	(0.008)	-	(0.014 BSC*)	-	-	(0.026 BSC*)	-	

* BSC — Basic Spacing between Centers

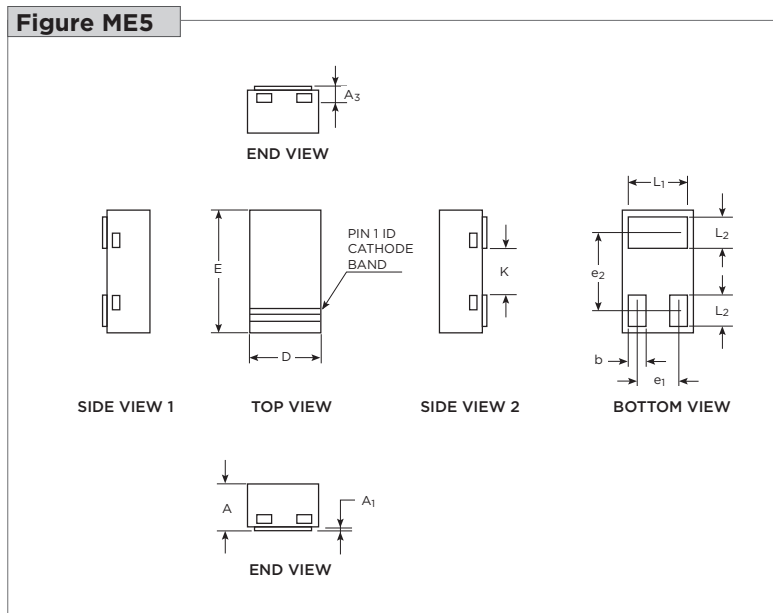


Table ME5 SESD Landing Pad Layout 3 Pin 2-ch 0402 Size Array

Symbol	Millimeters (mm)	Inches (in)
A	0.60	0.024
B	1.00	0.039
C	0.23	0.009
D	0.35	0.014
D ₁	0.35	0.014
E	0.15	0.006
F	0.30	0.012

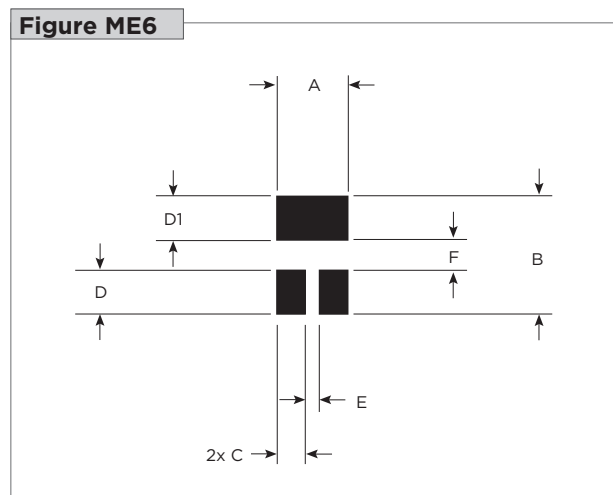
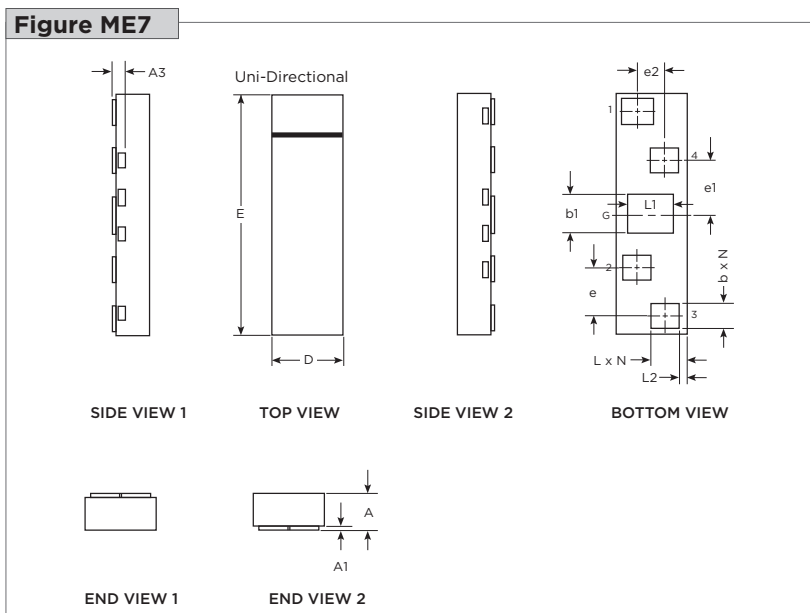


Table ME6 Device Dimensions for SESD Devices in Millimeters and (Inches)
Part Number
SESD0802Q4UG-0020-090

A			A ₁			A ₃			D			E			b			b ₁		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.33	0.38	0.43	0	0.02	0.05	-	0.127 ref.	-	0.50	0.60	0.70	1.90	2.00	2.10	0.15	0.20	0.25	0.25	0.30	0.36
(0.013)	(0.015)	(0.017)	(0)	-	(0.002)	-	(0.005 ref.)	-	(0.020)	(0.024)	(0.028)	(0.075)	(0.079)	(0.083)	(0.006)	(0.008)	(0.010)	(0.010)	(0.012)	(0.014)

L			L ₁			L ₂			e			e ₁			e ₂			N			Figure			
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.25	0.30	0.36	0.35	0.40	0.45	-	0.05 BSC*	-	-	0.40 BSC*	-	-	0.45 BSC*	-	-	0.25 BSC*	-	-	4	-	-	4	-	ME7
(0.010)	(0.012)	(0.014)	(0.014)	(0.016)	(0.018)	-	(0.002 BSC*)	-	-	(0.016 BSC*)	-	-	(0.018 BSC*)	-	-	(0.010 BSC*)	-	-	4	-	-	4	-	

* BSC — Basic Spacing between Centers


Table ME7 SESD Landing Pad Layout 5 Pin 4-ch Miniature FT Array

Symbol	Millimeters (mm)	Inches (in)
A	0.60	0.024
B	2.00	0.079
C	0.30	0.012
D	0.30	0.012
E	0.30	0.012
F	0.10	0.004
F ₁	0.15	0.006
G	0.40 BSC*	0.016 BSC*
G ₁	0.45 BSC*	0.018 BSC*

* BSC — Basic Spacing between Centers

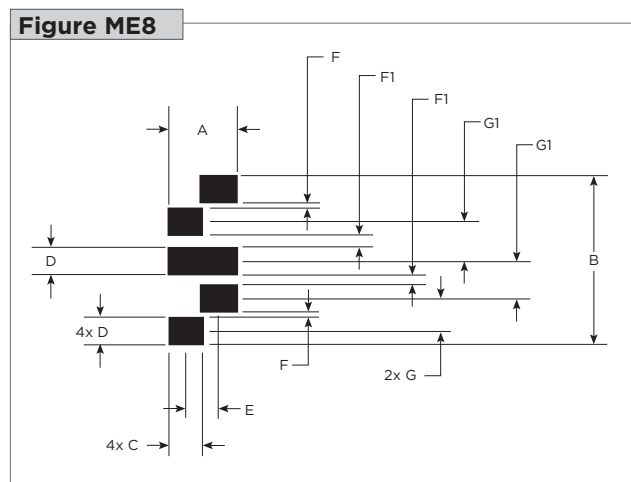


Table ME8 Device Dimensions for SESD Devices in Millimeters and (Inches)

Part Number
SESD1004Q4UG-0020-090

A			A ₁			A ₃			D			E			b			b ₁		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.33	0.38	0.43	0	0.02	0.05	-	0.127 ref.	-	0.90	1.00	1.10	2.40	2.50	2.60	0.15	0.20	0.25	0.35	0.40	0.45
(0.013)	(0.015)	(0.017)	(0)	-	(0.002)	-	(0.005 ref.)	-	(0.035)	(0.039)	(0.043)	(0.094)	(0.098)	(0.102)	(0.006)	(0.008)	(0.010)	(0.014)	(0.016)	(0.018)

L			L ₁			e			e ₁			N			R			R ₁			Figure
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.33	0.38	0.43	0.00	0.10	0.15	-	0.50 BSC*	-	-	0.50 BSC*	-	-	10	-	-	0.075 BSC*	-	-	0.125 BSC*	-	ME9
(0.013)	(0.015)	(0.017)	(0.000)	(0.004)	(0.006)	-	(0.020 BSC*)	-	-	(0.020 BSC*)	-	-	10	-	-	(0.003 BSC*)	-	-	(0.005 BSC*)	-	

* BSC — Basic Spacing between Centers

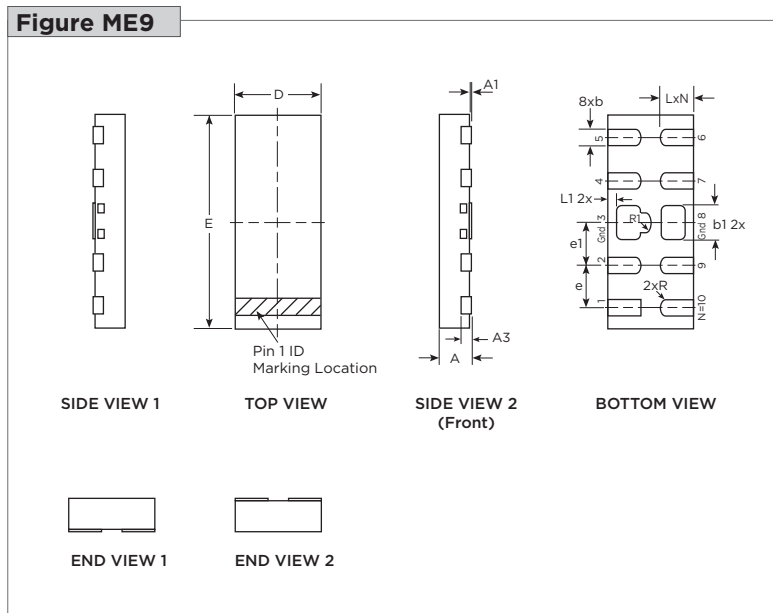


Table ME9 SESD Landing Pad Layout 3 Pin 2-ch 0402 Size Array

Symbol	Millimeters (mm)	Inches (in)
A	1.20	0.047
B	2.20	0.087
C	0.50	0.020
D	0.20	0.008
D ₁	0.40	0.016
E	0.20	0.008
F	0.30	0.012
F ₁	0.20	0.008
G	0.50 BSC*	0.020 BSC*
G ₁	1.00 BSC*	0.039 BSC*

* BSC — Basic Spacing between Centers

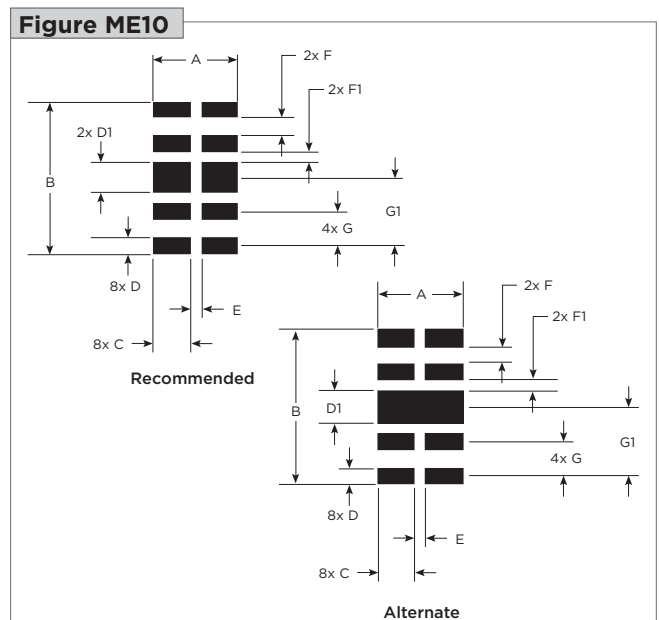
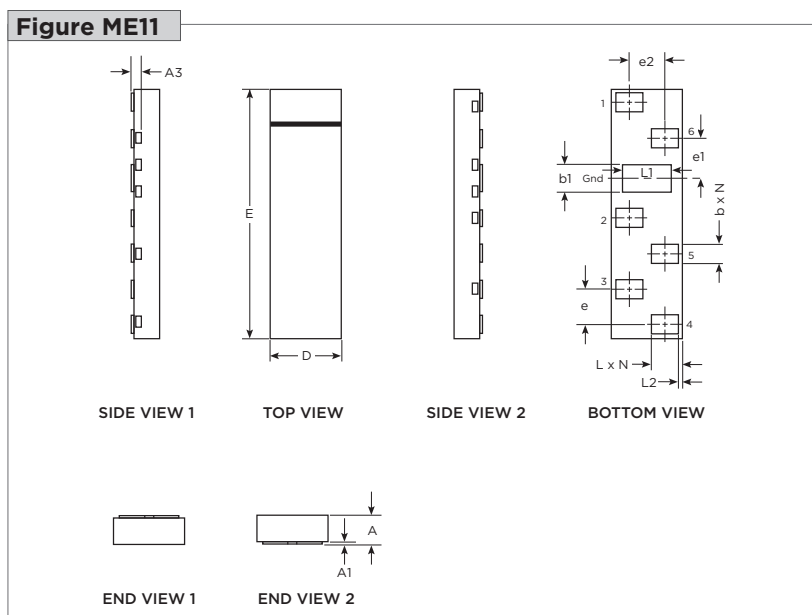


Table ME10 Device Dimensions for SESD Devices in Millimeters and (Inches)
Part Number
SESD1103Q6UG-0020-090

A			A ₁			A ₃			D			E			b			b ₁		
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
0.33	0.38	0.43	0	0.02	0.05	-	0.127 ref.	-	0.70	0.80	0.90	2.70	2.80	2.90	0.15	0.20	0.25	0.25	0.30	0.35
(0.013)	(0.015)	(0.017)	(0)	-	(0.002)	-	(0.005 ref.)	-	(0.027)	(0.031)	(0.035)	(0.106)	(0.110)	(0.114)	(0.006)	(0.008)	(0.010)	(0.010)	(0.012)	(0.014)

L			L ₁			L ₂			e			e ₁			e ₂			N			Figure			
Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
0.30	0.35	0.40	0.50	0.55	0.60	-	0.05 BSC*	-	-	0.40 BSC*	-	-	0.45 BSC*	-	-	0.40 BSC*	-	-	6	-	-	6	-	ME11
(0.012)	(0.014)	(0.016)	(0.019)	(0.021)	(0.024)	-	(0.002 BSC*)	-	-	(0.016 BSC*)	-	-	(0.018 BSC*)	-	-	(0.016 BSC*)	-	-	6	-	-	6	-	

* BSC — Basic Spacing between Centers


Table ME11 SESD Landing Pad Layout 5 Pin 4-ch Miniature FT Array

Symbol	Millimeters (mm)	Inches (in)
A	0.80	0.031
B	2.80	0.110
C	0.35	0.014
D	0.30	0.012
E	0.45	0.018
F	0.10	0.004
F ₁	0.15	0.006
G	0.40 BSC*	0.016 BSC*
G ₁	0.45 BSC*	0.018 BSC*

* BSC — Basic Spacing between Centers

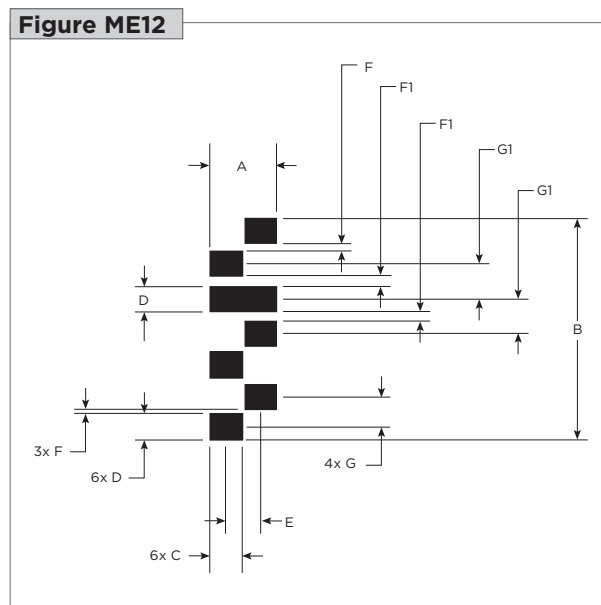
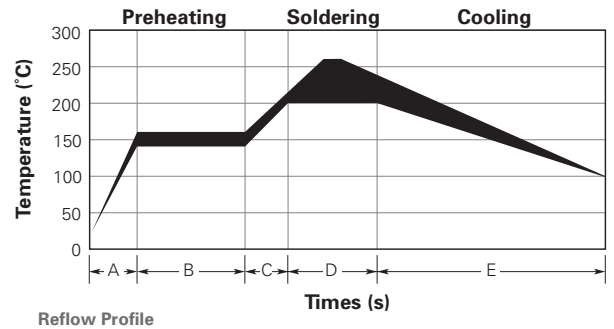


Table ME12 Solder Reflow Recommendations for ESD Devices

A	Temperature Ramp-up 1	From Ambient to Preheating Temperature	30s to 60s
B	Preheating	140°C - 160°C	60s to 120s
C	Temperature Ramp-up 2	From Preheating to Main Heating Temperature	20s to 40s
D	Main Heating	at 200°C at 220°C at 240°C at 260°C	60s to 70s 50s to 60s 30s to 40s 5s to 10s
E	Cooling	From Main Heating Temperature to 100°C	4°C/s max


Table ME13 Carrier Tape Specifications

Tape Dimension EIA Mark	SESD00402Q		SESD0802Q		SESD1004Q		SESD1103Q	
	Dimension (mm)	Tolerance	Dimension (mm)	Tolerance	Dimension (mm)	Tolerance	Dimension (mm)	Tolerance
W	8.00	± 0.05	8.00	+0.30 / -0.10	8.00	+0.30 / -0.10	8.00	+0.30 / -0.10
zP ₀	4.00	±0.10	4.00	±0.10	4.00	±0.10	4.00	±0.10
P ₁	2.00	±0.05	2.00	±0.10	4.00	±0.10	4.00	±0.10
P ₂	2.00	±0.05	2.00	±0.05	2.00	±0.05	2.00	±0.05
A ₀	0.70	±0.05	0.81	±0.05	1.20	±0.05	1.00	±0.05
B ₀	1.15	±0.05	2.21	±0.05	2.70	±0.05	3.00	±0.05
D ₀	Ø1.55	±0.05	Ø1.50	+0.10 / -0.00	Ø1.50	+0.10 / -0.00	Ø1.50	+0.10 / -0.00
D ₁	Ø0.40	±0.05	Ø0.40 (min)	-	Ø0.50 (min)	-	Ø0.50 (min)	-
E ₁	1.75	±0.10	1.75	±0.10	1.75	±0.10	1.75	±0.10
F	3.50	±0.05	3.50	±0.05	3.50	±0.05	3.50	±0.05
K ₀	0.47	±0.05	0.46	±0.05	0.51	±0.05	0.51	±0.05
T	0.20	±0.05	0.25	±0.20	0.25	±0.05	0.25	±0.05
Detail A	-	3° (max)	-	-	-	-	-	-

Note 1. All dimensions in mm
 Note 2. Measured from centerline of pocket to centerline of sprocket hole
 Note 3. Cumulative tolerance of 10 sprocket holes is ±0.20
 Note 4. Tolerances unless noted ±0.20

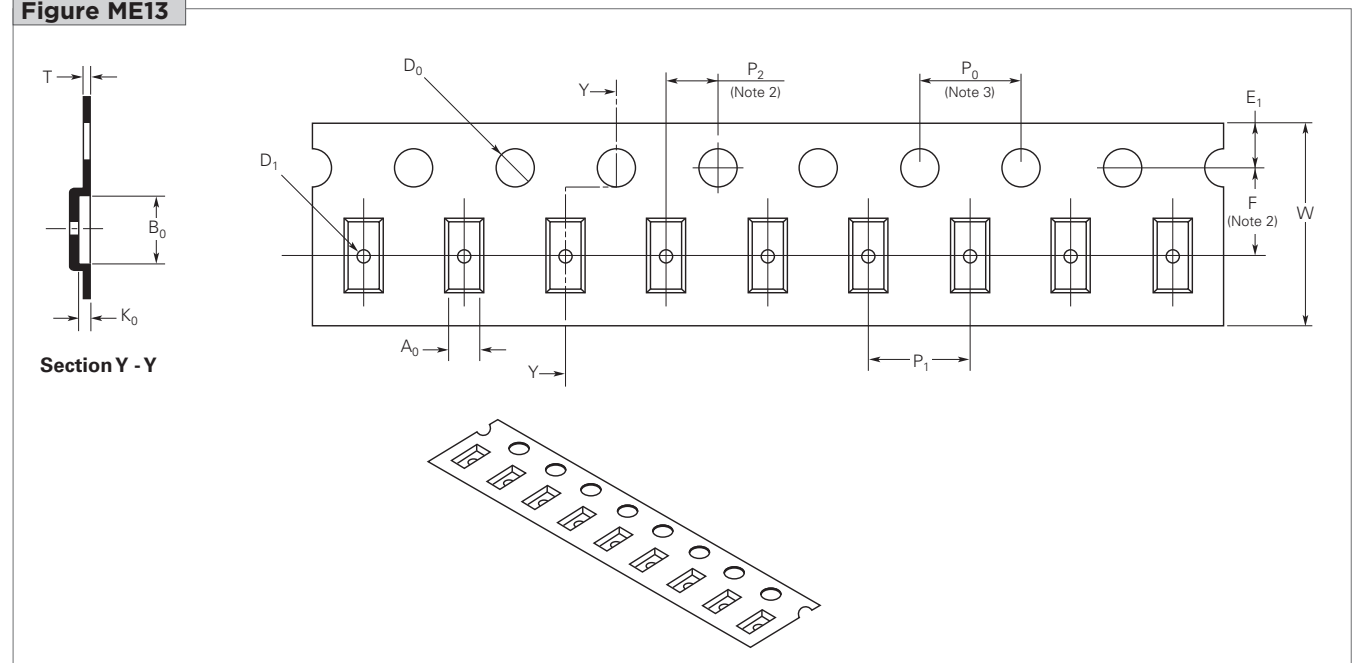
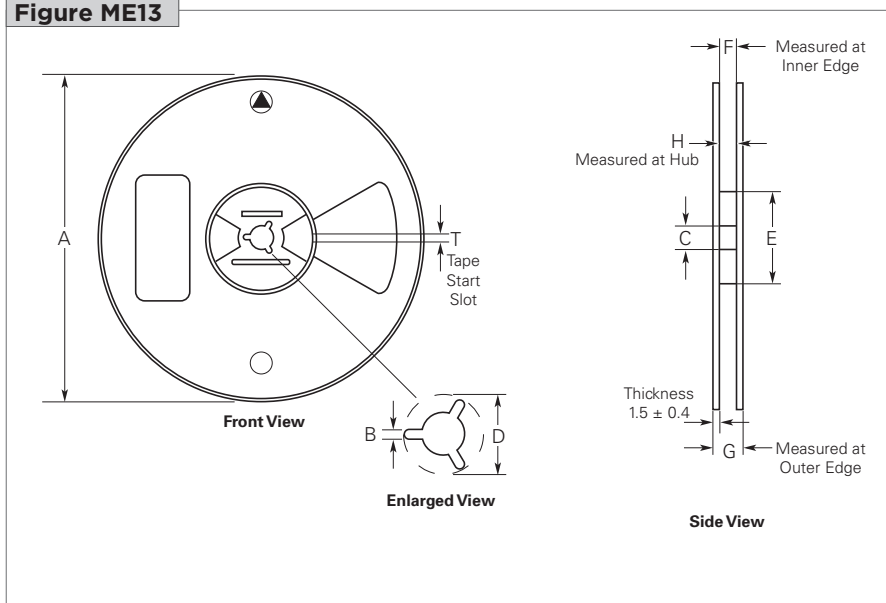
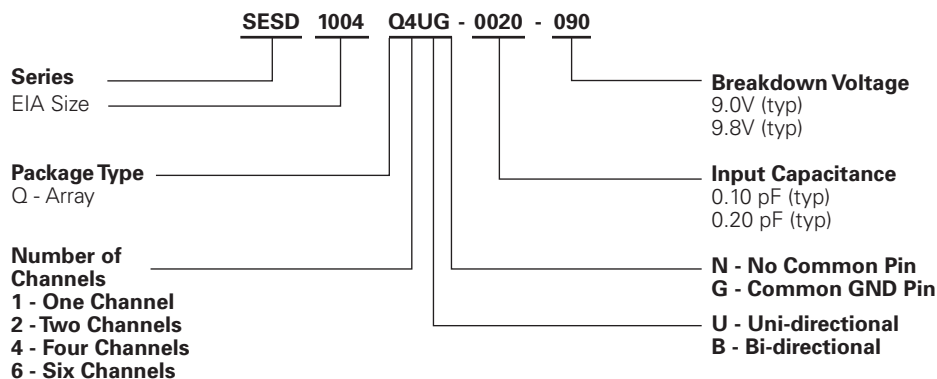
Figure ME13


Table ME14 Reel Specifications

Reel Dimension EIA Mark	Dimension (mm)
A	180 ± 2.00
B	1.50 (min)
C	13.10 ± 0.20
D	20.20 (min)
E	60 ± 1.00
F	8.75 ± 1.00
G	11.6 ± 1.00
H	9.4 (max)

Figure ME13

Part Numbering System for Multi-Channel Silicon ESD Devices

Part Marking

Part Number	Part Marking
SESD0402Q2UG-0020-090 (2-ch)	C
SESD0802Q4UG-0020-090 (4-ch)	MC
SESD1004Q4UG-0020-090 (4-ch)	4C
SESD1103Q6UG-0020-090 (6-ch)	6C